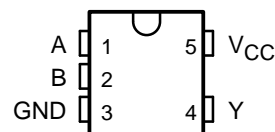


SN74AHC1G32 SINGLE 2-INPUT POSITIVE-OR GATE

SCLS317A – MARCH 1996 – REVISED MAY 1996

- Operating Range: 2-V to 5.5-V V_{CC}
- **EPIC™** (Enhanced-Performance Implanted CMOS) Process
- High Latch-Up Immunity Exceeds 250 mA Per JEDEC Standard JESD-17
- Packaged in Plastic Small-Outline Transistor Package

DBV PACKAGE
(TOP VIEW)



description

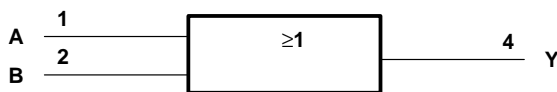
The SN74AHC1G32 is a single 2-input positive-OR gate. The device performs the Boolean function $Y = A + B$ or $Y = \overline{A} \bullet \overline{B}$ in positive logic.

The SN74AHC1G32 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE

INPUTS		OUTPUT
A	B	Y
H	X	H
X	H	H
L	L	L

logic symbol†



logic diagram (positive logic)



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

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SN74AHC1G32

SINGLE 2-INPUT POSITIVE-OR GATE

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–0.5 V to 7 V
Output voltage range, V_O (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	– 20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	± 20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	± 25 mA
Continuous current through V_{CC} or GND	± 50 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air)(see Note 2)	0.2 W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 25 millimeters.

recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	2	5.5	V
V_{IH}	High-level input voltage	$V_{CC} = 2$ V	1.5	V
		$V_{CC} = 3$ V	2.1	
		$V_{CC} = 5.5$ V	3.85	
V_{IL}	Low-level input voltage	$V_{CC} = 2$ V	0.5	V
		$V_{CC} = 3$ V	0.9	
		$V_{CC} = 5.5$ V	1.65	
V_I	Input voltage	0	5.5	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 2$ V	– 50	μA
		$V_{CC} = 3.3$ V ± 0.3 V	– 4	mA
		$V_{CC} = 5$ V ± 0.5 V	– 8	
I_{OL}	Low-level output current	$V_{CC} = 2$ V	50	μA
		$V_{CC} = 3.3$ V ± 0.3 V	4	mA
		$V_{CC} = 5$ V ± 0.5 V	8	
$\Delta t/\Delta v$	Input transition rise or fall rate	$V_{CC} = 3.3$ V ± 0.3 V	100	ns/V
		$V_{CC} = 5$ V ± 0.5 V	20	
T_A	Operating free-air temperature	– 40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	T _A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
V _{OH}	I _{OH} = – 50 µA	2 V	1.9	2		1.9		V
		3 V	2.9	3		2.9		
		4.5 V	4.4	4.5		4.4		
	I _{OH} = – 4 mA	3 V	2.58			2.48		
	I _{OH} = – 8 mA	4.5 V	3.94			3.8		
V _{OL}	I _{OL} = 50 µA	2 V			0.1		0.1	V
		3 V			0.1		0.1	
		4.5 V			0.1		0.1	
	I _{OL} = 4 mA	3 V			0.36		0.44	
	I _{OL} = 8 mA	4.5 V			0.36		0.44	
I _I	A or B inputs	V _I = V _{CC} or GND	5.5 V		± 0.1		± 1	µA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	5.5 V		2		20	µA
C _i		V _I = V _{CC} or GND	5 V		2	10	10	pF

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	T _A = 25°C			MIN	MAX	UNIT
				MIN	TYP	MAX			
t _{PLH}	A or B	Y	C _L = 15 pF		5.5	7.9	1	9.5	ns
t _{PHL}					5.5	7.9	1	9.5	
t _{PLH}	A or B	Y	C _L = 50 pF		8	11.4	1	13	ns
t _{PHL}					8	11.4	1	13	

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	T _A = 25°C			MIN	MAX	UNIT
				MIN	TYP	MAX			
t _{PLH}	A or B	Y	C _L = 15 pF		3.8	5.5	1	6.5	ns
t _{PHL}					3.8	5.5	1	6.5	
t _{PLH}	A or B	Y	C _L = 50 pF		5.3	7.5	1	8.5	ns
t _{PHL}					5.3	7.5	1	8.5	

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load, f = 1 MHz	14	pF

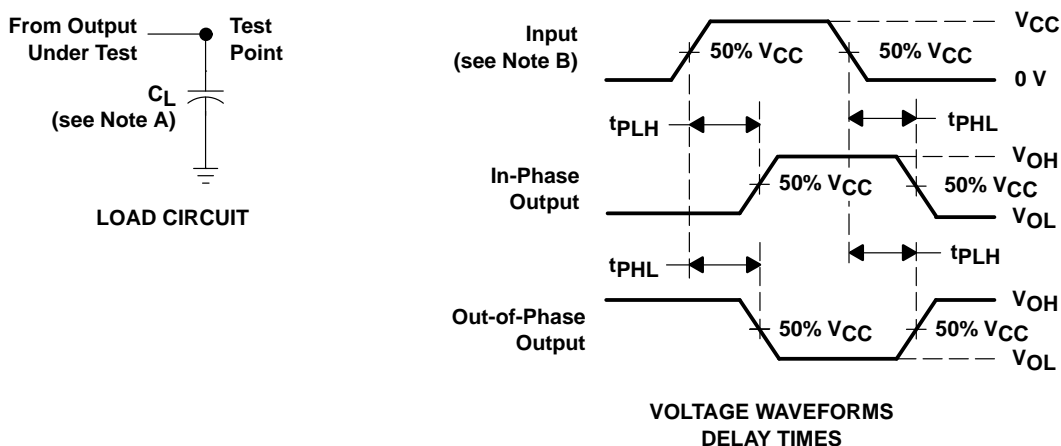


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SINGLE 2-INPUT POSITIVE-OR GATE

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PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_L includes probe and jig capacitance.
 B. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1$ MHz, $Z_O = 50 \Omega$, $t_r = 3$ ns, $t_f = 3$ ns.
 C. The output is measured with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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